TOSHIBA Field Effect Transistor Silicon N Channel MOS Type

SSM3K01F

High Speed Switching Applications

- Small package
- Low on resistance: Ron = 120 m Ω (max) (VGS = 4 V)

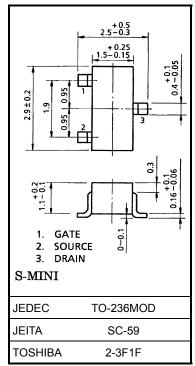
 $: \text{Ron} = 150 \text{ m}\Omega \text{ (max)} \text{ (VGS} = 2.5 \text{ V)}$

• Low gate threshold voltage: $V_{th} = 0.6 \sim 1.1 \text{ V} (V_{DS} = 3 \text{ V}, \text{I}_D = 0.1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V _{DS}	30	V	
Gate-source voltage		V _{GSS}	±10	V	
Drain current	DC	I _D	1.3	A	
	Pulse	I _{DP}	2.6		
Drain power dissipation		PD	200	mW	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

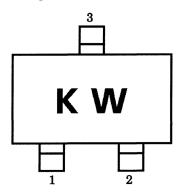
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.



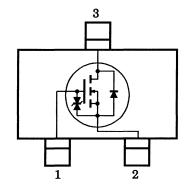
Weight: 0.012 g (typ.)

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Marking



Equivalent Circuit



Handling Precaution

When handling individual devices (which are not yet mounted on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

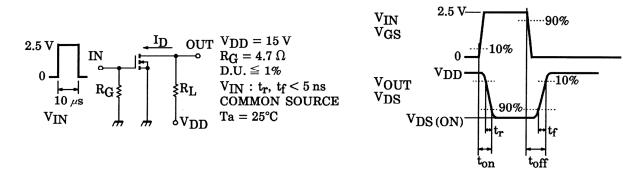
Unit: mm

Electrical Characteristics (Ta = 25°C)

Chara	Characteristics Symbol Test Condition		Min	Тур.	Max	Unit	
Gate leakage current		I _{GSS}	$V_{GS}=\pm 10~V,~V_{DS}=0$	—		±5	μΑ
Drain-source breakdown voltage		V (BR) DSS	$I_D = 1 \text{ mA}, V_{GS} = 0$		_		V
Drain cut-off curre	ent	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0$	-	_	1	μA
Gate threshold vo	oltage	V _{th}	$V_{DS} = 3 \text{ V}, \text{ I}_{D} = 0.1 \text{ mA}$	0.6	_	1.1	V
Forward transfer	admittance	Y _{fs}	$V_{DS} = 3 \text{ V}, \text{ I}_{D} = 0.65 \text{ A} \qquad (\text{Note}$) 2.0	_		S
Drain-source ON resistance		R _{DS} (ON)	$I_D = 0.65 \text{ A}, V_{GS} = 4 \text{ V}$ (Note) —	85	120	mΩ
			$I_D = 0.65 \text{ A}, V_{GS} = 2.5 \text{ V}$ (Note) —	115	150	
Input capacitance		C _{iss}	$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0, \text{ f} = 1 \text{ MHz}$		152		pF
Reverse transfer capacitance		C _{rss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	—	41		pF
Output capacitance		C _{oss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	—	102		pF
Switching time	Turn-on time	t _{on}	V_{DD} = 15 V, I_D = 0.5 A, V_{GS} = 0~2.5 V, R_G = 4.7 Ω	_	45		ns
	Turn-off time	t _{off}		—	69		

Note: Pulse test

Switching Time Test Circuit



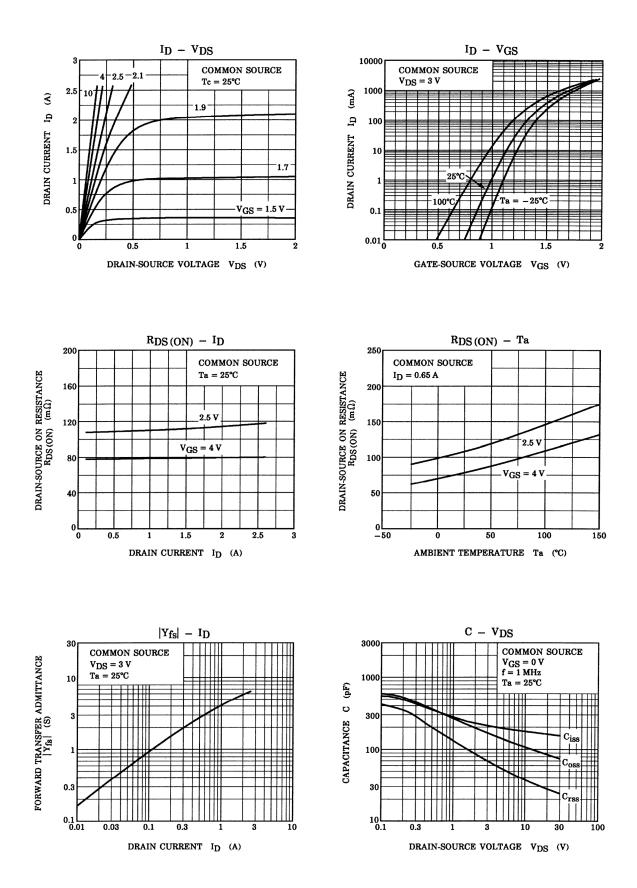
Precaution

 V_{th} can be expressed as voltage between gate and source when low operating current value is I_D = 100 μA for this product. For normal switching operation, V_{GS} (ON) requires higher voltage than V_{th} and V_{GS} (off) requires lower voltage than V_{th} .

(Relationship can be established as follows: VGS (off) < Vth < VGS (ON))

Please take this into consideration for using the device.

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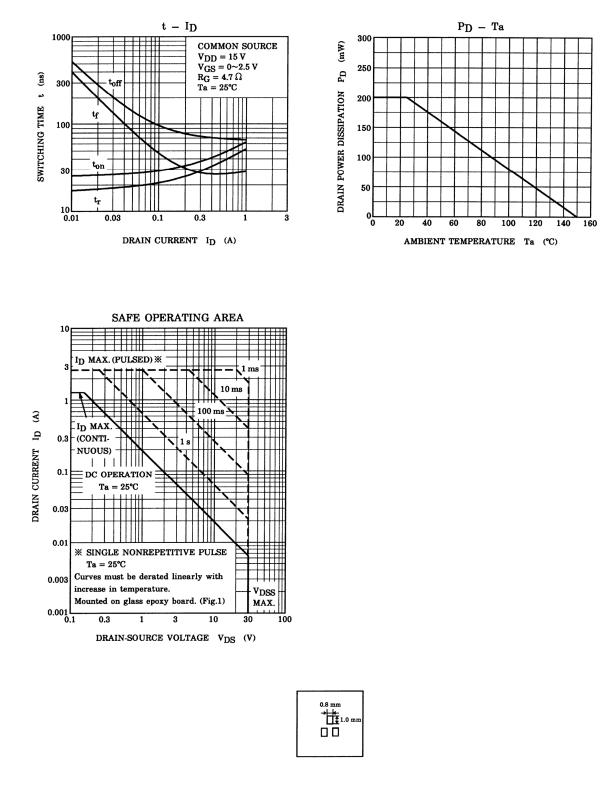


Figure 1 25.4 mm \times 25.4 mm \times 1.6 t (a Cu pad of 0.8 mm² area)

RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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 In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
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